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IAP11 Rec'd 07/26/2006

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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128865	APPLICATION NO. New U.S. National Phase of PCT/JP2005/001225
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANTS Hiroaki TAKAIWA et al.		
		FILING DATE July 26, 2006		

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Examiner Initials	Cite No.	Document Number	Date	Name
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Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)				

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DATE CONSIDERED 06/06/2008

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: July 26, 2006 ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /ML/

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